	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments
1	BRS	L1	3159	probe$1 near25 actuator$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/09 13:54	
2	BRS	L2	926	probe$1 near25 actuator$1 near25 mov$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/09 13:55	
3	BRS	L3	84	probe$1 near25 actuator$1 near25 mov$3 near25 perpendicular	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/09 14:38	

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments
4	BRS	L4	14753	array near5 probes	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/09 14:38	
5	BRS	L5	1513	(array near5 probes) near15 (dimensional)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/09 14:39	
6	BRS	L6	774	(array near5 probes) near15 (two-dimensional)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/09 14:39	

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments
7	BRS	L7	21	(array near5 probes) near15 (two-dimensional) near15 (one-dimensional)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/09 14:44	
8	BRS	L8	1	(probes near chip) near15 (two-dimensional) near15 (one-dimensional)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/09 14:44	
9	BRS	L9	1	(probe near chip) near15 (two-dimensional) near15 (one-dimensional)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/09 14:45	

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments
10	BRS	L10	67	(probe$1) near15 (two-dimensional) near15 (one-dimensional)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/09 16:30	
11	BRS	L11	3	(probe near chip) near15 (two-dimensional)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/09 16:13	
12	BRS	L12	13	(probe near chip) near15 (dimension)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/09 16:13	

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments
13	BRS	L13	8	(probe near chip) near15 ($-dimensional)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/09 16:14	
14	BRS	L14	289	(probe$1) near15 (one-dimensional)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/09 16:15	

	U	1	Document ID	Title	Current OR	Pages
1	☐	☐	US 20040119490 A1	Parallel, individually addressable probes for nanolithography	324/765	15
2	☒	☐	US 20020182610 A1	Method for making probe support and apparatus used for the method	435/6	47
3	☐	☐	US 5824481 A	DNA analyzing method	435/6	16
4	☐	☐	US 5650274 A	DNA analyzing method	435/6	16
5	☐	☐	JP 11153427 A	COORDINATES MEASURING MACHINE		46
6	☒	☐	JP 09251319 A	POSITIONING UNIT FOR FINE POSITIONING DEVICE		8
7	☒	☐	JP 06051831 A	TWO-DIMENSIONAL POSITION ADJUSTING DEVICE		4
8	☒	☐	US 20040119490 A	Pattern forming apparatus for e.g. Dip Pen Nanolithography, comprises probe chip having probe array, first actuator for moving the probe chip, second actuators for selectively raising or lowering each probe tip, and actuating source		15